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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Hajime KOMURA et al.

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Filing Date: May 4, 2007

Examiner: West, Paul M.

Group Art Unit: 2856

Date: April 4, 2008



U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor/Applicant Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclosed	No
	GR	0 060 944 A	09/1982	EP	Westinghouse Electric Corp.				
	HR	03/019169 A1	03/2003	WO	Sugimura Et al.	X			
	IR	0 902 279 A1	03/1999	EP	NGK Spark Plug Co.				
	JR	0 731 351 A2	09/1996	EP	NGK Insulators Ltd.				
	KR	0 903 576 A2	03/1999	EP	NGK Spark Plug Co.				
	LR	2003-42989	02/2003	JP	Figaro Eng Inc	X			
	MR	54-24095	02/1979	JP	Fuji Electric Co Ltd	X			
	NR								
	OR								
	PR								

OTHER (including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

	QR	European Search Report mailed January 10, 2008 issued in EP Application No. 05 70 3821				
	RR	Horrillo et al., "Influence of the deposition conditions of SnO ₂ thin films by reactive sputtering on the sensitivity of urban pollutants", <i>Sensors and Actuators B</i> 45 (1997) pp. 193-198				
	SR	Skafidas et al., "Modelling and simulation of tin oxide based thick-film gas sensors using Monte Carlo techniques", <i>Sensors and Actuators B</i> , Vol. B19, No. 1-3, part 2, April 1994, pp. 724-728; (Abstract attached, Proceedings of the EUROSENSORS VII Conference, Budapest, Hungary, September 26-29, 1993)				
	TR					
	UR					
	VR					
	WR					
	XR					

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.